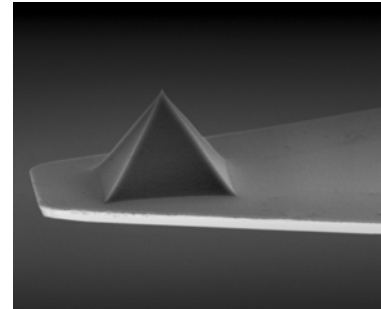


NanoWorld™ Introduces Hybrid-Nitride AFM Probe

Neuchâtel/Switzerland, August 1, 2004.

NanoWorld today officially introduced its new Hybrid-Nitride AFM probe for contact-mode.



Hybrid-Nitride™ AFM Probe

The Hybrid-Nitride™ probe combines silicon nitride cantilevers and tips with unique features like single holder chips for easy handling, single holder design to avoid breaking residue, rounded shoulder design to prevent mechanical contact between chip and sample and a notch design of the holder chip for clear indication of the cantilever type.

For further information please refer to our website at www.nanoworld.com or contact us at info@nanoworld.com.